

AVD/AVS

AUTOMOTIVE SERDES TEST TOOLS

FUNCTIONAL TEST FOR AUTOMOTIVE SERDES DEVICES



PRODUCT

Applications: Functional Test for Automotive SerDes Devices in Production and Validation



















Variants of the NOFFZ AVD & AVS based on different video chipsets and matching connector types

FEATURES AND HIGHLIGHTS

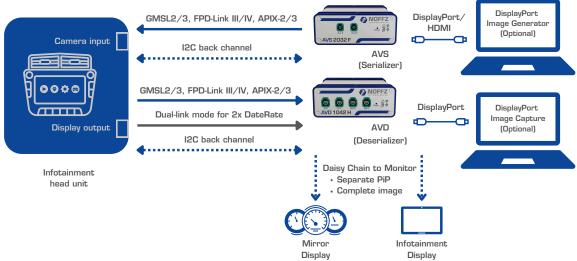
- > High throughput: Data rates up to 13 Gbps
- > I2C back-channel communication: Seamlessly control your chip, enable selftesting and built-in test signal generation.*
- > Internal pixel clock generation: No need for external source.
- > Daisy chaining option*: Expand your test system capabilities with daisy chaining, monitor test frames on real displays, separate PiP (picture-in-picture) from main image.
- > Multi-DUT testing: With the HDS platform you can switch multiple high-speed, differential video lines to a single AVD (deserializer), and store the image with a cost-efficient display port capture device.

SUPPORTS

Our test tools are compatible with the latest protocols, ensuring versatility and future-proofing your testing setup. For exact video chip variants, please, contact us.

- > GMSL2/3
- > FPD-Link III/IV
- > APIX-2/3*

INFOTAINMENT DEVICE TEST WITH VIDEO SERIALIZER AND DESERIALZER



SPECIFICATIONS

Interfaces (Front Panel)	AVS: 2x serial output on HFM (or H-MTD) connectors AVD: 2x serial input on H-MTD (or HFM) connectors 2x serial output on H-MTD (or HFM) connectors for daisy-chaining
Interfaces (Back Panel)	AVS: 1x Display Port (or HDMI) image input, 1x Ethernet/LAN for DC power AVD: 2x Display Port image output (dual-mode, PiP), 1x Ethernet/LAN for DC power
Supported Chipsets	Maxim (Analog Devices) and TI (request for details)
Temperature	Maximum operating temperature range: 0 °C to 85 °C; maximum environmental temperature is 35 °C
Operating Voltage	Unregulated 9 V to 36 V (12 V, 0.5 A recommended)

^{*} Only applicable on certain models